

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC7S00F, TC7S00FU**2-INPUT NAND GATE**

The TC7S00 is a high speed C²MOS 2-INPUT NAND GATE fabricated with silicon gate C²MOS technology.

It achieves high speed operation similar to equivalent LSTTL while maintaining the C²MOS low power dissipation.

The internal circuit is composed of 3 stages including buffer output, which enables high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

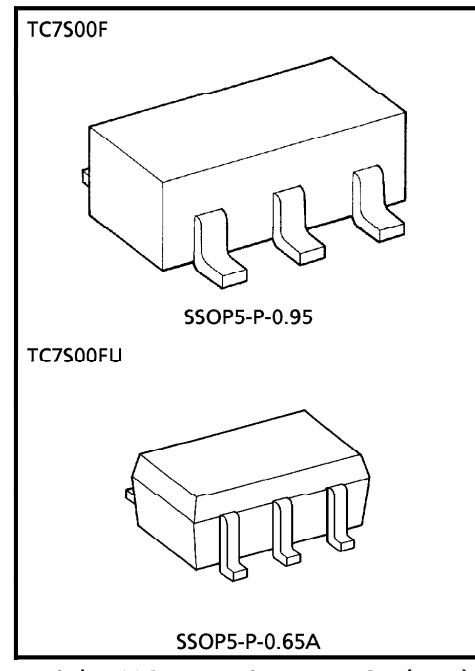
Output currents are 1/2 compared to TC74HC series models.

FEATURES

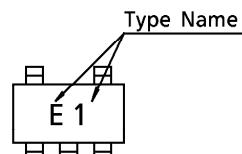
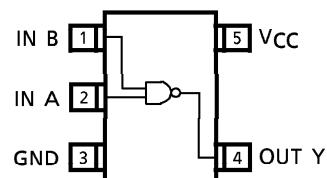
- High Speed $t_{pd} = 7\text{ns}$ (Typ.) at $V_{CC} = 5\text{V}$
- Low Power Dissipation $I_{CC} = 1\mu\text{A}$ (Max.) at $T_a = 25^\circ\text{C}$
- High Noise Immunity $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (Min.)
- Output Drive Capability 5 LSTTL Loads
- Symmetrical Output Impedance ... $|I_{OH}| = I_{OL} = 2\text{mA}$ (Min.)
- Balanced Propagation Delays $t_{pLH} = t_{pHL}$
- Wide Operating Voltage Range ... $V_{CC(\text{opr})} = 2\sim 6\text{V}$

MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage Range	V_{CC}	$-0.5\sim 7$	V
DC Input Voltage	V_{IN}	$-0.5\sim V_{CC} + 0.5$	V
DC Output Voltage	V_{OUT}	$-0.5\sim V_{CC} + 0.5$	V
Input Diode Current	I_{IK}	± 20	mA
Output Diode Current	I_{OK}	± 20	mA
DC Output Current	I_{OUT}	± 12.5	mA
DC V_{CC} / Ground Current	I_{CC}	± 25	mA
Power Dissipation	P_D	200	mW
Storage Temperature	T_{stg}	$-65\sim 150$	°C
Lead Temperature (10s)	T_L	260	°C



Weight SSOP5-P-0.95 : 0.016g (Typ.)
SSOP5-P-0.65A : 0.006g (Typ.)

MARKING**PIN ASSIGNMENT (TOP VIEW)**

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● TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.

LOGIC DIAGRAM



RECOMMENDED OPERATING CONDITIONS

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V_{CC}	2~6	V
Input Voltage	V_{IN}	0~ V_{CC}	V
Output Voltage	V_{OUT}	0~ V_{CC}	V
Operating Temperature	T_{opr}	-40~85	°C
Input Rise and Fall Time	t_r, t_f	0~1000 ($V_{CC} = 2.0V$) 0~ 500 ($V_{CC} = 4.5V$) 0~ 400 ($V_{CC} = 6.0V$)	ns

DC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	SYMBOL	TEST CONDITION	V_{CC}	Ta = 25°C			Ta = - 40~85°C		UNIT
				MIN.	TYP.	MAX.	MIN.	MAX.	
High-Level Input Voltage	V_{IH}	—	2.0	1.5	—	—	1.5	—	V
			4.5	3.15	—	—	3.15	—	
			6.0	4.2	—	—	4.2	—	
Low-Level Input Voltage	V_{IL}	—	2.0	—	—	0.5	—	0.5	V
			4.5	—	—	1.35	—	1.35	
			6.0	—	—	1.8	—	1.8	
High-Level Output Voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = - 20\mu A$	2.0	1.9	2.0	—	1.9	V
			$I_{OH} = - 2mA$	4.5	4.4	4.5	—	4.4	
			$I_{OH} = - 2.6mA$	6.0	5.9	6.0	—	5.9	
		$V_{IN} = V_{IH}$	$I_{OH} = - 20\mu A$	4.5	4.18	4.31	—	4.13	V
			$I_{OH} = - 2mA$	6.0	5.68	5.80	—	5.63	
			$I_{OH} = - 2.6mA$	2.0	—	0.0	0.1	—	
Low-Level Output Voltage	V_{OL}	$V_{IN} = V_{IH}$	$I_{OL} = 20\mu A$	4.5	—	0.0	0.1	—	V
			$I_{OL} = 2mA$	6.0	—	0.0	0.1	—	
		$V_{IN} = V_{IL}$	$I_{OL} = 2.6mA$	4.5	—	0.17	0.26	—	
			$I_{OL} = 2.6mA$	6.0	—	0.18	0.26	—	
Input Leakage Current	I_{IN}	$V_{IN} = V_{CC}$ or GND	6.0	—	—	± 0.1	—	± 1.0	μA
Quiescent Supply Current	I_{CC}	$V_{IN} = V_{CC}$ or GND	6.0	—	—	1.0	—	10.0	

Output currents are 1/2 compared to TC74HC series models.

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AC ELECTRICAL CHARACTERISTICS ($C_L = 15\text{pF}$, Input $t_r = t_f = 6\text{ns}$, $V_{CC} = 5\text{V}$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	Ta = 25°C			UNIT
			MIN.	TYP.	MAX.	
Output Transition Time	t_{TLH} t_{THL}	—	—	5	10	ns
Propagation Delay Time	t_{pLH} t_{pHL}	—	—	7	15	ns

AC ELECTRICAL CHARACTERISTICS ($C_L = 50\text{pF}$, Input $t_r = t_f = 6\text{ns}$)

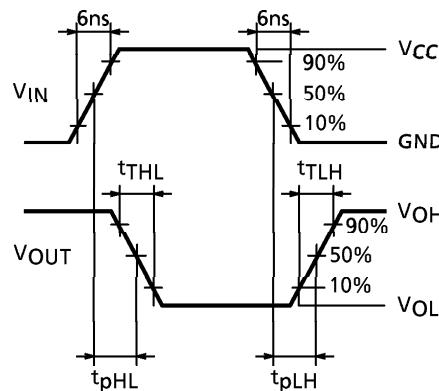
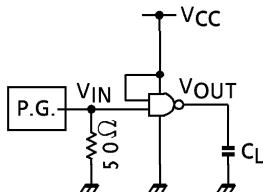
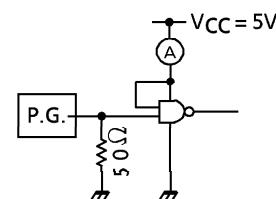
CHARACTERISTIC	SYMBOL	TEST CONDITION	V_{CC}	Ta = 25°C		Ta = -40~85°C		UNIT
				MIN.	TYP.	MAX.	MIN.	
Output Transition Time	t_{TLH}	—	2.0	—	50	125	—	155
	t_{THL}		4.5	—	14	25	—	31
			6.0	—	12	21	—	26
Propagation Delay Time	t_{pLH}	—	2.0	—	48	100	—	125
	t_{pHL}		4.5	—	12	20	—	25
			6.0	—	9	17	—	21
Input Capacitance	C_{IN}	—	—	—	5	10	—	10
Power Dissipation Capacitance	C_{PD}	(Note 1)	—	—	10	—	—	—

Note 1 : C_{PD} defined as the value of internal equivalent capacitance of IC which is calculated from the operating current consumption without load (refer to Test Circuit).

Average operating current can be obtained by the equation hereunder.

$$I_{CC(\text{opr})} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

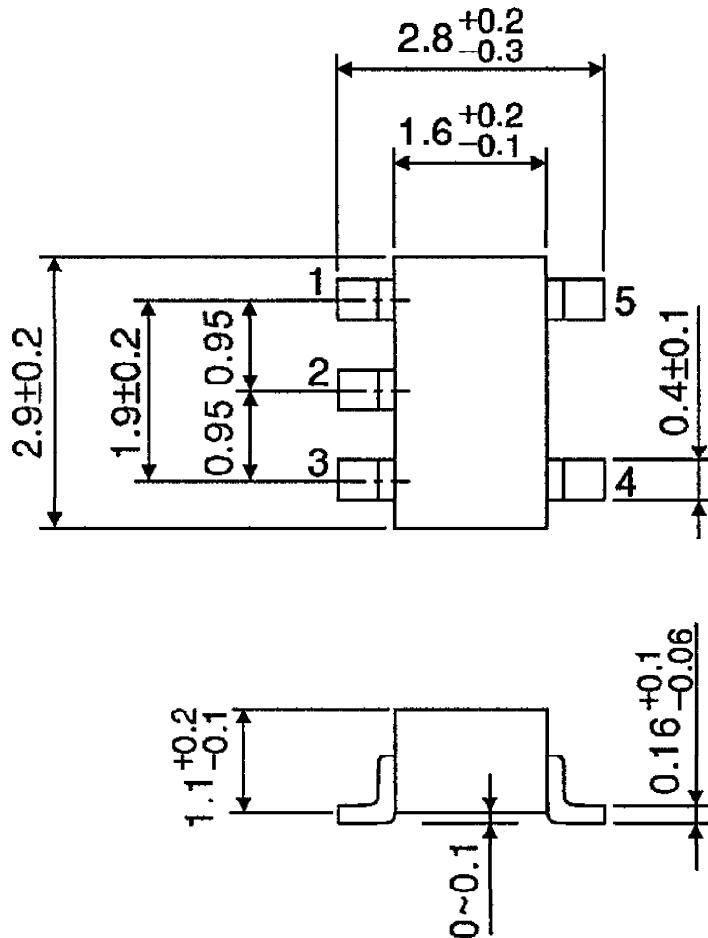
SWITCHING CHARACTERISTICS TEST CIRCUIT

 $I_{CC(\text{opr})}$ TEST CIRCUIT

input waveform is the same as that in case of switching characteristics test.

OUTLINE DRAWING
SSOP5-P-0.95

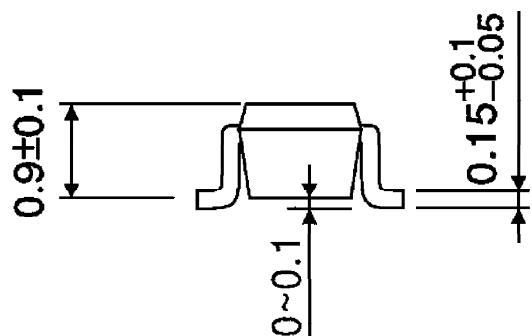
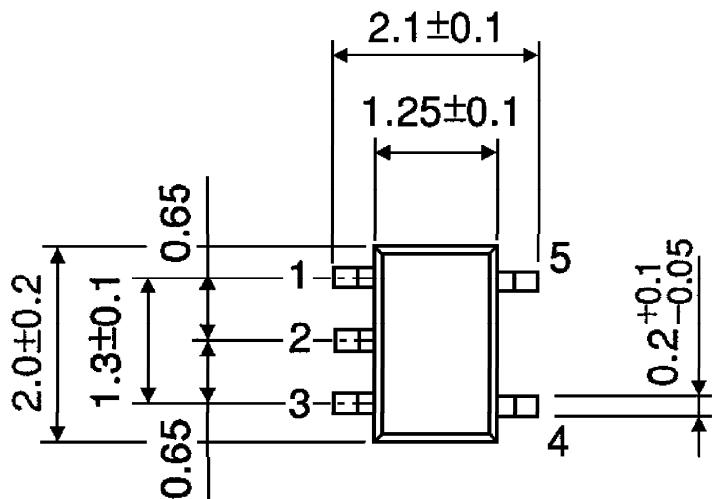
Unit : mm



Weight : 0.016g (Typ.)

OUTLINE DRAWING

Unit : mm



Weight : 0.006g (Typ.)